



ANALYSIS & SOURCING

BY THAOSEN

Buyer: [REDACTED]

Host organization: [REDACTED]

Period: [REDACTED]

Sourcing area: Asia , China

SUMMARY

--- Freemium Report ---

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2 - Client request

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--- You want to manage the operation without us ? Get Premium Report ---

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Introduction

We have received the purchasing intention from [REDACTED] asked us to source relative product (precious metal analyzer) in Chinese market. To clarify the requirement, [REDACTED] they intend to choose precious metal analyzer with good quality from China, meanwhile, they need to maximize the mobility and portability of the device in order to facilitate usage and operation.

The team of THAOSEN had done a market research for one week, managing to review various types of metal analyzers in China. We will show a report below that was divided into different aspects to introduce the product. We expect our report can make our client understand better about the targeted goods in Chinese market and make a best decision for its future business.



Characteristics:

- [REDACTED]
- [REDACTED]
- [REDACTED]

Abstract

Precious metals require — and reward — careful analysis. Their high monetary value means that purity is a prime consideration when trading in these metals or products made from them. Different alloys must be identified and their composition verified. Adulteration, while not always easy to detect, can dramatically affect value.

Analysts face various difficulties. The scope of precious metals analysis extends from trace levels to 100%. Most of these metals are resistant to dissolution by all but the strongest acids. Some traditional analytical methods like **fire assay** are **time-consuming and demand a high level of skill**.

Three modern techniques offer widely used solutions. **Energy-dispersive X-ray fluorescence (ED-XRF)** and **optical emission spectrometry (OES)** can be used without specialist analytical training to rapidly and accurately analyze bullion, jewelry, and alloys. A variation of OES, **inductively coupled plasma optical emission spectrometry (ICP-OES)**, is an ideal tool for the analysis of bulk materials such as ores, and for the determination of trace impurities.

All three methods work on the **spectroscopic principle**, which relies on the internal **structure of the atoms** of the material being analyzed. The atoms of the sample are excited by an external source of energy, which is absorbed by and raises the energy level of the electrons in the sample atoms. This excited state is unstable, so the electrons rapidly return to their normal state, re-emitting energy as they do so. The energy emitted, or emission spectrum, is characteristic of the elements contained in the sample; its intensity is proportional to their concentration. **The techniques differ in the type of energy used to excite the sample atoms** (which also governs the type of samples that can be handled), and in the technology used to **analyze and detect the emitted radiation**. The following table summarizes the main features of the techniques and their uses in precious metals analysis:

Technique	Excitation	Spectrum Analysis	Detection	Typical Analyses
ED-XRF	X-rays from low power (40 W or less) X-ray tube	Solid state Silicon Drift Detector (SDD) or Si PIN Detector, capable of discriminating between emissions from different elements.		Purity of solid metals eg bullion, pin samples, coins, jewelry. PM's in bulk recycled materials catalysts, electronic waste
OES	Electric arc or spark discharge	Optical polychromator using diffraction grating	CCD and/or photomultiplier	Impurities in metals, eg bullion, pin samples
ICP-OES	Inductively coupled plasma	Optical polychromator using diffraction grating	CCD and/or photomultiplier	Traces of PM's in fire assay "buttons". Impurities in PM's and alloys,

ED-XRF Analysis

ED-XRF spectrometers are based on the energy-dispersive-X-ray-fluorescence analysis method. The **atoms** in the sample material, which could be any solid, powder or liquid are excited by X-Rays emitted from an **X-Ray tube** or **radioisotope**. For increasing sensitivity, the primary excitation radiation can be polarized by using specific targets between the X-Ray tube and the sample (ED-P(polarization)-XRF). All element **specific X-Ray fluorescence signals** emitted by the atoms after the **photoelectric ionization** are measured simultaneously in a fixed mounted semi-conductor detector or sealed gas-proportional counter.

The **radiation intensity of each element signal**, which is proportional to the concentration of the element in the sample, is recalculated internally from a stored set of calibration curves and can be **shown directly in concentration units**.

ED-XRF is the most widely used analytical technique in the precious metals industry. Unlike many spectroscopic techniques, it **doesn't require the sample to be atomized** to enable excitation. It can **analyze solid samples directly**. Unlike methods requiring fusion or dissolution, it's **nondestructive**. This is critical to its usefulness in analyzing jewelry and other valuable items without damage or removal of precious metal. Finally, it's ideal for the detection of counterfeiting and for other forensic work.



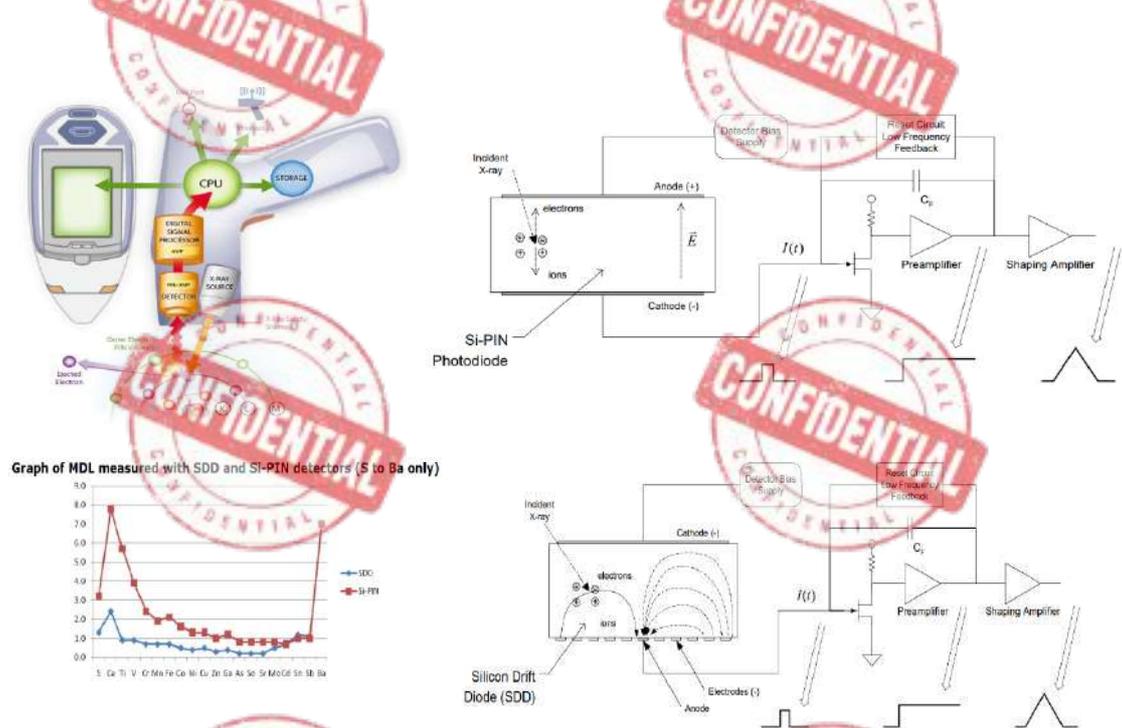
WHY ED-XRF?

- **Easy to operate without complex chemical reagent.**
- **Direct to use without damaging the sample.**
- **Being used in the most of analyzers, fulfilling the need of portability.**
- **More choices of device to choose.**
- **Meeting the client's main requirement.**

Core Component Comparison

➤ Detectors: Silicon Drift (SDD) vs. PIN-Diode (Si-PIN)

Most lines of XRF Spectrometers will typically offer a model with a proportional counter detection system (for basic coating thickness measurements) and have additional systems with higher resolution detector technology, either **Silicon Drift Detection (SDD)** or **Si-PIN Diode Detectors (Si-PIN)** for elemental analysis interests. The sensitivity and performance at different energies when equipped with different detectors is expressed in the **minimum detection limits (MDL)** of the different elements.



- ✓ The Si-PIN is available with a larger active area and thicker depletion depth. Where resolution is not critical but **high detection efficiency** and **lower cost** are important, **Si-PIN is the detector of choice**. **To distinguish 999, 9999 gold. (0.05% accuracy)**
- ✓ The SDD is a more complicated device to manufacturer so is **more expensive** than a Si-PIN. The SDD has **better energy resolution** than a Si-PIN of the same area. The SDD has much better energy resolution at short peaking times, which is particularly helpful at **high count rates**. So where the highest resolution is needed, or where good resolution is needed at high count rates, **the SDD is the detector of choice**. **To distinguish 9993, 9995, 9997, 9999 gold. (0.01% accuracy)**

Western Market

ThermoFisher SCIENTIFIC

Thermo Fisher Scientific is an American biotechnology product development company located in Waltham, Massachusetts, and was created in 2006 by the merger of Thermo Electron and Fisher Scientific. In April 2013, after a competitive bidding with Hoffmann-La Roche, Thermo Fisher acquired Life Technologies Corporation for US\$13.6 billion in a deal that would rank the firm as one of the leading companies in the genetic testing and precision laboratory equipment markets.



SPECTRO is a manufacturer of elemental analyzers using optical emission spectroscopy and x-ray fluorescence spectrometry. The company's headquarters are located in Kleve, Germany. It was founded in 1979 and specialized in metal analyzers based on optical emission (arc/spark). These were later followed by elemental analyzers based on inductively coupled plasma (ICP) optical emission and x-ray fluorescence (XRF) spectrometry. SPECTRO is a major provider of analytical instrumentation with an installed base of over 30,000 spectrometers worldwide. In 2005, SPECTRO became part of AMETEK's Material Analysis Division.



Main Selling Category in China



[REDACTED] device dedicated to screening and analysis of harmful elements restricted by RoHS / ELV regulations. Its integrated halogen-free analysis technology is equipped with an intelligent vacuum system. It uses low-energy X-rays to excite light elements and detects any harmful halogens. At the same time, material products are also suitable for all-element and ROHS analysis. It has the advantages of high analysis accuracy, a wide range of analyzable elements, and simple and fast testing. The results are reliable and accurate, and meet the new national standard.



[REDACTED] devices are recognized for ruggedness and reliability on the job. They offer metals or nonmetals identification in seconds, with innovative technologies and designs that provide repeatable, laboratory-quality results. Simple, user-friendly displays and efficient ergonomics make these instruments extremely easy to use.



[REDACTED] is designed for safe, high-quality energy dispersive X-ray fluorescence (EDXRF) analysis in the field. This high-performance instrument is equipped with a secure closed-ray sample compartment, and its flexible analysis software can perform a variety of factory default and user-defined calibrations without the need for sample preparation. The collection and analysis operations are simple and convenient, and their functions are comparable to a mobile laboratory.



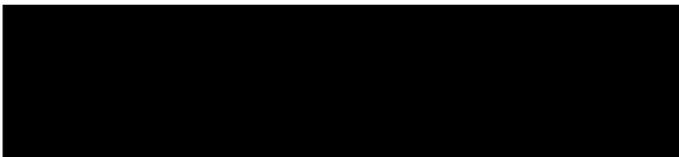
[REDACTED]

Model A Handheld Analyzer

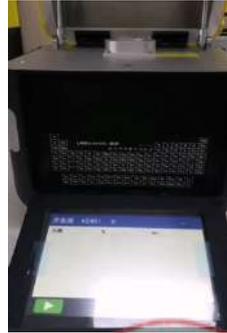


Weight net	1.6Kg (including battery)
Device size (mm)	254 x 79 x 280 (L x W x H)
Excitation source	
Detector	
Detection range	
Display system	
Data Processing	
Heat dissipation	
Safety level	
Power system	

Price:

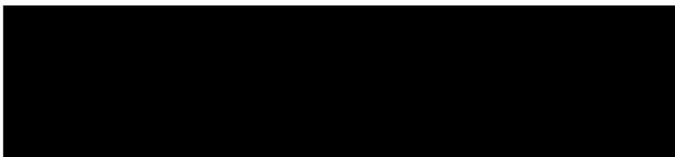


Model B Mobile X-ray Lab



Device size (mm)
Sample Chamber (mm)
Gross Weight
Excitation source
Detector
OS
Power system
Resolution
Data transmit
Operating temperature
Operating humidity
Screen
Testing time
Safety level
Characteristic

Price:



Supplier Profile

Not available in Freemium report

Co., Ltd.

Location	Map
Business organization	
Registered capital	
Date of establishment	
Sector	
Business scope	
Employee	
Patent	
OEM	
ODM	

Model C Desktop Analyzer



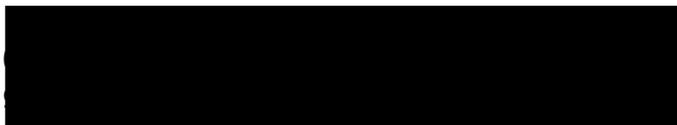
Quick Features:

- Provides Accuracy close to Fire Assay Standards.
- Uses Advanced Amptek USA Si-Pin Diode Detector.
- 100% Human Safe.
- Life Time Maintenance Support.

Working Principle
Precision
Operating Environment
High Voltage:
Detector:
Resolution:
Testable Elements:
Inbuilt Computer
Inbuilt Touch Screen
Printer
X-ray Source
Input Voltage
Rated Power
Size(mm):
N/G Weight(KG):

Need to be plugged in when working

Price:



Model D Desktop Analyzer

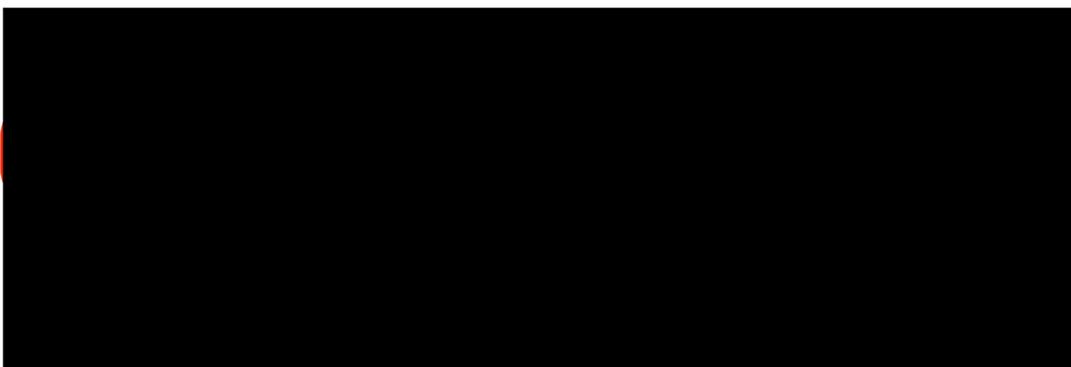


Quick Features:

- Italian designed Portable XRF Gold Analyzer
- Detects 20+ Elements Precisely close to Fire Assay
- Identifies Prohibited Elements (Powder) Iridium, Ruthenium, Osmium, etc.
- Lead (Pb) glass to guarantee 100% human safe
- One Key to Test
- Simple software and user interface makes it easy to operate

Working Principle:	
Precision:	
Operating Environment:	
Integrated X-Ray Generator	
Detector:	
Resolution:	
Testable Elements:	
Inbuilt Computer	
Inbuilt Touch Screen	
Cover material	
Input Voltage	
Rated Power	
Instrument dimension(mm):	
Testing chamber dimension (mm)	
N/G Weight(KG):	

Need to be plugged in when working



Supplier Profile

Not available in Freemium report

Co., Ltd

Location	Map
Business organization	
Registered capital	
Date of establishment	
Sector	
Business scope	
Employee	
Patent	
OEM	
ODM	

Transportation Solution

Ocean Shipping

Shipping company	Delivery time	Fee
MSC	Premium Service	
MAERSK		
CMA CGM		
YML		

Thaosen Comment

This part of text is proposed to provide clients the comment that has been issued by Thaosen purchasing team when we analyze the market and communicate with targeted suppliers above in China, which could facilitate buyers to make a most suitable choice through referring to more detailed and implicit information. We always spare no efforts to offer supply side situation via the most completed dimension.

Premium Service

Question Remaining

